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<u>L9</u>	702/57-60,79.ccls.	1136	<u>L9</u>
<u>L8</u>	438/7,16.ccls.	857	<u>L8</u>
<u>L7</u>	700/121.ccls.	881	<u>L7</u>
<u>L6</u>	324/158.1,537,750, 752, 753.ccls.	37647	<u>L6</u>

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<u>L5</u>	L1 and temperature	338	<u>L5</u>
<u>L4</u>	L1 and temperature	338	<u>L4</u>
<u>L3</u>	L1 and ((cross adj talk\$3) or victim or aggressor)	28	<u>L3</u>
<u>L2</u>	L1 and CMOS	65	<u>L2</u>
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**1 Dynamic internal testing of CMOS circuits using hot luminescence**
*Kash, J.A.; Tsang, J.C.;*

Electron Device Letters, IEEE , Volume: 18 , Issue: 7 , July 1997

Pages:330 - 332

[\[Abstract\]](#)   [\[PDF Full-Text \(56 KB\)\]](#)   **IEEE JNL**
**2 CMOS-circuit degradation analysis using optical measurement of the substrate current**
*Romano, G.; Sampietro, M.;*

Electron Devices, IEEE Transactions on , Volume: 44 , Issue: 5 , May 1997

Pages:910 - 912

[\[Abstract\]](#)   [\[PDF Full-Text \(80 KB\)\]](#)   **IEEE JNL**

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